

# FQA9N90C 900V N-Channel MOSFET

# **Features**

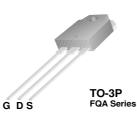
- 9A, 900V,  $R_{DS(on)}$  = 1.4 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 45 nC)
- Low Crss (typical 14pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability

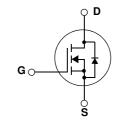


# Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies, active power factor correction, electronic lamp ballast based on half bridge topology.





# **Absolute Maximum Ratings**

Symbol		Parameter		FQA9N90C	Units
V <sub>DSS</sub>	Drain-Source Vo	rce Voltage		900	V
I <sub>D</sub>	Drain Current	- Continuous (T <sub>C</sub> = 25°C)		9.0	А
		- Continuous (T <sub>C</sub> = 100°C)		5.7	А
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	36	А
V <sub>GSS</sub>	Gate-Source Vol	tage		$\pm 30$	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy		(Note 2)	900	mJ
I <sub>AR</sub>	Avalanche Current		(Note 1)	9.0	А
E <sub>AR</sub>	Repetitive Avala	nche Energy	(Note 1)	28	mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	4.0	V/ns
P <sub>D</sub>	Power Dissipatio	Power Dissipation ( $T_{\rm C}$ = 25°C)		280	W
		- Derate above 25°C		2.22	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and S	torage Temperature Range		-55 to +150	°C
TL	Maximum lead te	emperature for soldering purposes,			

# **Thermal Characteristics**

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<b>Device Marking</b>		Device	Packag	e Re	Reel Size	Тар	Tape Width		Quantity	
FQA9N90C		FQA9N90C	TO-3P						30	
FQA9N90C FQA9N90C_F109 TO		TO-3PN	۰ ا				30			
						•				
	al Cha	racteristics T <sub>c</sub>	= 25°C unless othe	1				1	1	1
Symbol		Parameter		Test	Conditio	ns	Min	Тур	Max	Units
Off Charac	teristics									
BV <sub>DSS</sub>	Drain-So	urce Breakdown Voltag	ge	$V_{GS}$ = 0 V, $I_D$	= 250 μA		900			V
∆BV <sub>DSS</sub> / ∆T <sub>J</sub>	Breakdown Voltage Temperature Coefficient		$I_D$ = 250 µA, Referenced to 25°C			0.99		V/°C		
I <sub>DSS</sub>	Zero Gate Voltage Drain Current			V <sub>DS</sub> = 900 V,	V <sub>GS</sub> = 0 V				10	μA
				V <sub>DS</sub> = 720 V, T <sub>C</sub> = 125°C					100	μA
I <sub>GSSF</sub>	Gate-Boo	ly Leakage Current, F	orward	$V_{GS}$ = 30 V, $V_{DS}$ = 0 V					100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse		$V_{GS}$ = -30 V, $V_{DS}$ = 0 V				-100	nA		
On Charact	eristics							1		1
V <sub>GS(th)</sub>	Gate Thre	ate Threshold Voltage		$V_{DS}$ = $V_{GS}$ , $I_D$ = 250 $\mu$ A		3.0		5.0	V	
R <sub>DS(on)</sub>	Static Dra	tatic Drain-Source On-Resistance		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4.5 A			1.12	1.4	Ω	
9 <sub>FS</sub>	Forward Transconductance		$V_{DS} = 50 \text{ V}, I_D = 4.5 \text{ A}$ (Note 4)			9.2		S		
Dynamic Ch	naracteristi	ics							1	
C <sub>iss</sub>	Input Cap	out Capacitance tput Capacitance		V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz			2100	2730	pF	
C <sub>oss</sub>							175	230	pF	
C <sub>rss</sub>	Reverse Transfer Capacitance						14	18	pF	
Switching C	haracteris	tics		1						
t <sub>d(on)</sub>	Turn-On	Turn-On Delay Time		$V_{DD}$ = 450 V, I <sub>D</sub> = 11.0A, R <sub>G</sub> = 25 Ω			50	110	ns	
t <sub>r</sub>	Turn-On Rise Time Turn-Off Delay Time					120	250	ns		
t <sub>d(off)</sub>						100	210	ns		
t <sub>f</sub>	Turn-Off	Fall Time				(Note 4, 5)		75	160	ns
Qg	Total Gat	e Charge		V <sub>DS</sub> = 720 V, I <sub>D</sub> = 11.0A,				45	58	nC
Q <sub>gs</sub>	Gate-Sou	Irce Charge		V <sub>GS</sub> = 10 V				13		nC
Q <sub>gd</sub>	Gate-Dra	in Charge		-		(Note 4, 5)		18		nC
	e Diode C	haracteristics and Max	kimum Ratings					<u> </u>	1	<u> </u>
I <sub>S</sub>		n Continuous Drain-So							9.0	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward		d Current					36	Α	
V <sub>SD</sub>	Drain-So	urce Diode Forward Vo	oltage	$V_{GS}$ = 0 V, I <sub>S</sub>	=9.0 A				1.4	V
t <sub>rr</sub>	Reverse	Recovery Time		$V_{GS}$ = 0 V, I <sub>S</sub>				550		ns
Q <sub>rr</sub>	Reverse	Recovery Charge		dl <sub>F</sub> / dt = 100 A/μs		(Note 4)		6.5		μC

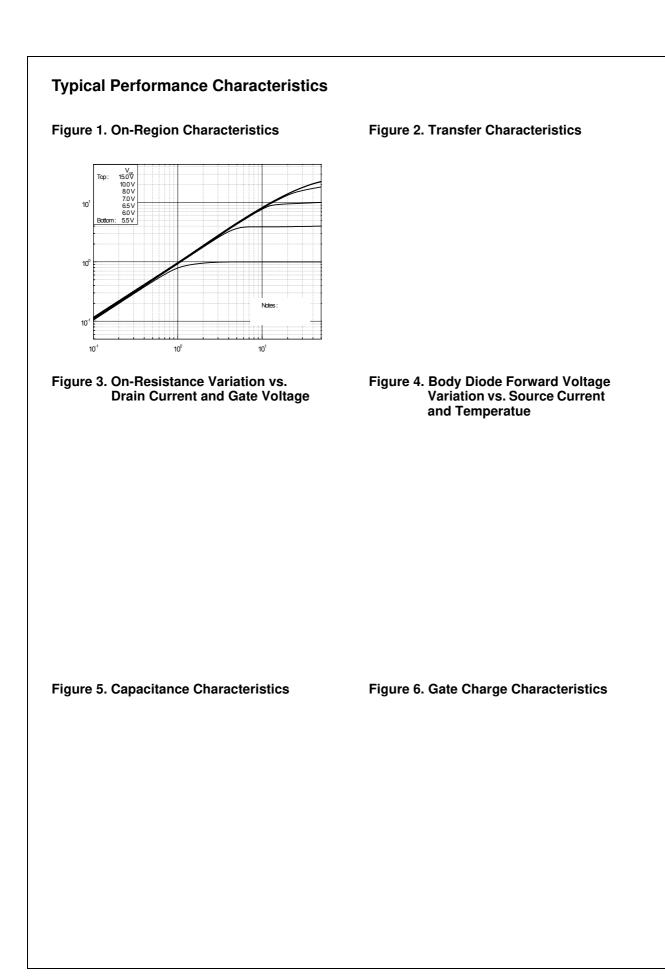
1. Repetitive Rating : Pulse width limited by maximum junction temperature

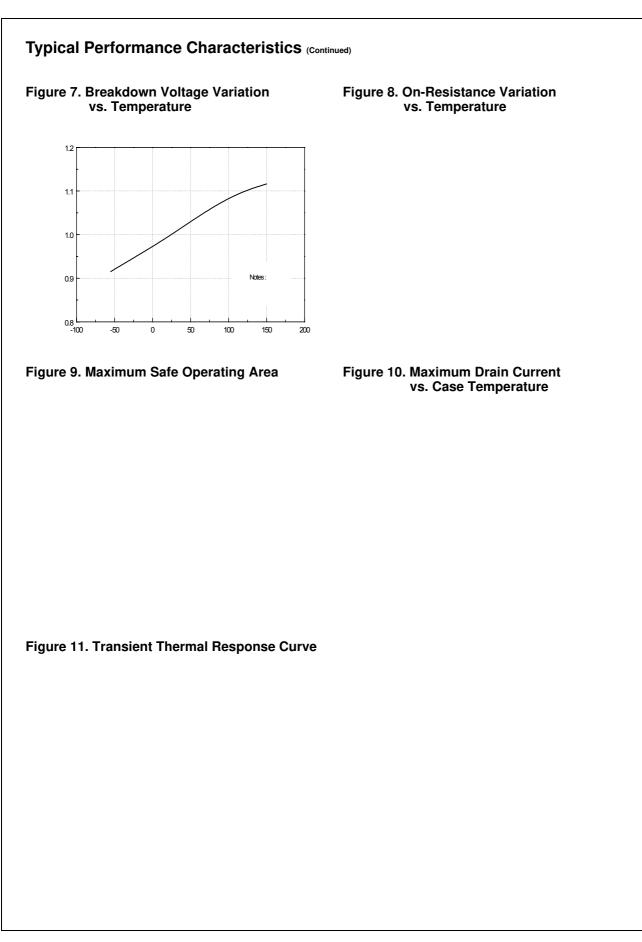
2. L = 21mH, I<sub>AS</sub> =9.0A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C

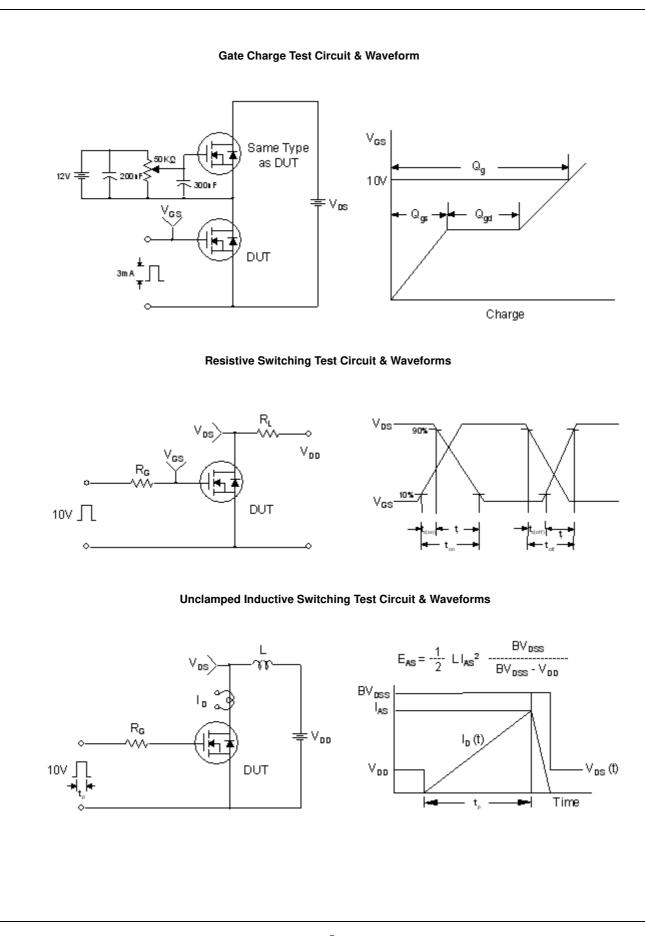
3. I\_{SD} \leq 9.0A, di/dt  $\leq$  200A/µs, V\_{DD}  $\leq$  BV\_{DSS,} Starting ~T\_J = 25°C

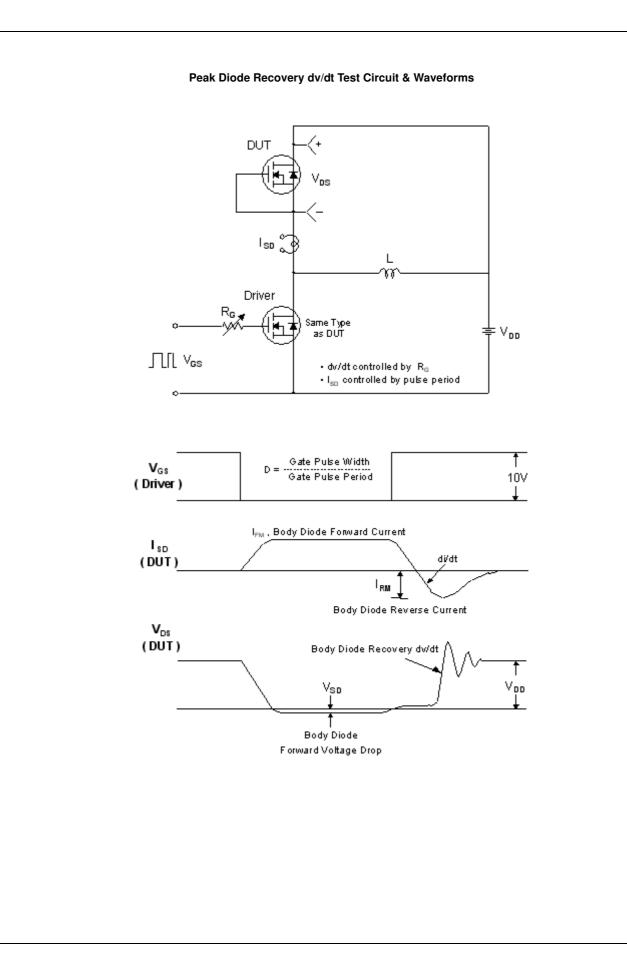
4. Pulse Test : Pulse width  $\leq 300 \mu s,$  Duty cycle  $\leq 2\%$ 

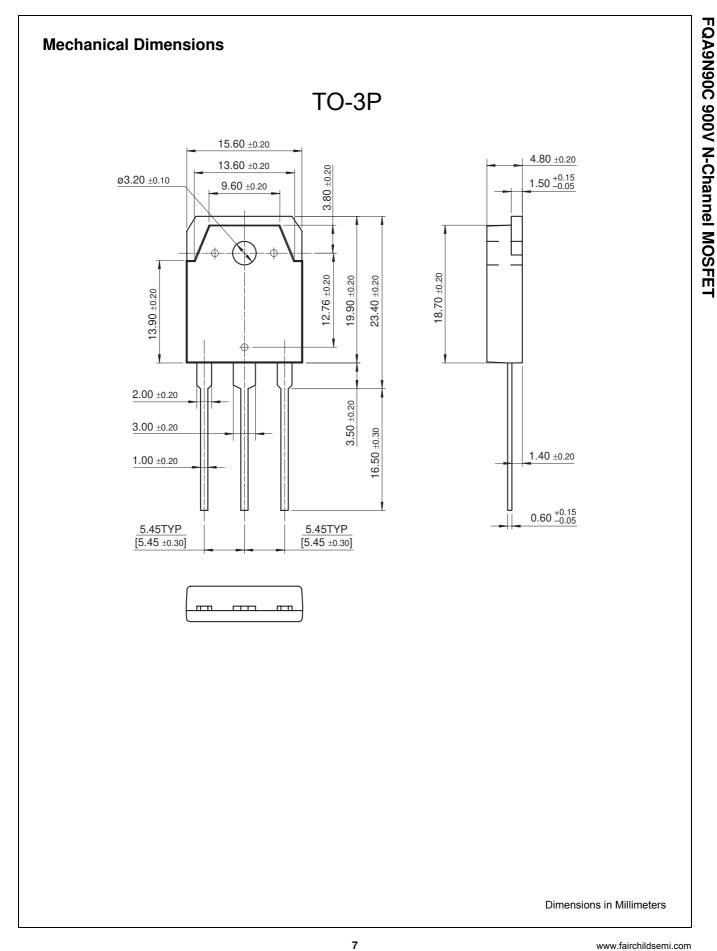
5. Essentially independent of operating temperature

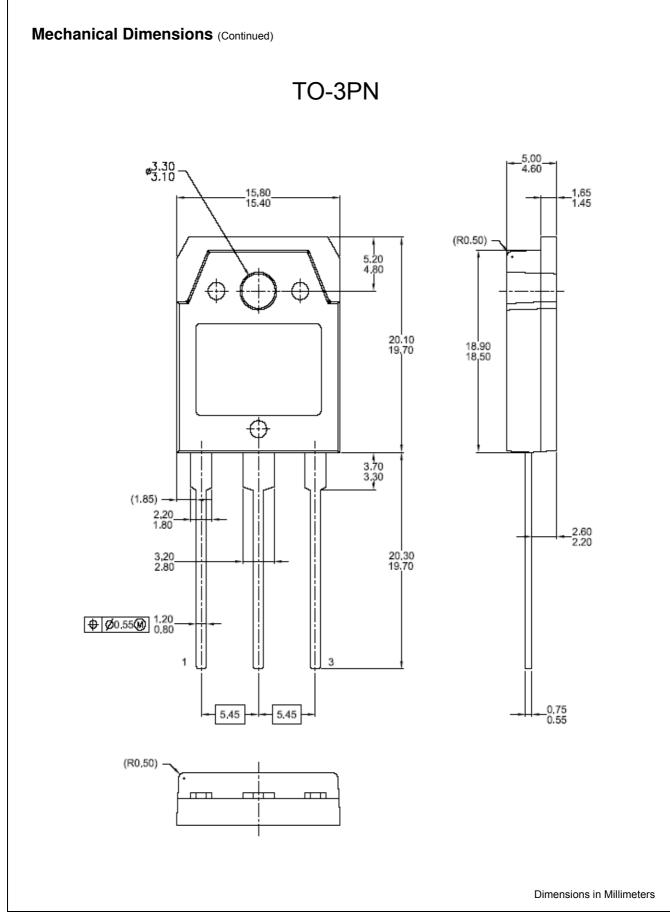












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